

## 2010 Summer School: “New Trends in Nano-scale Metrology”

We are pleased to announce the 2010 Summer School: “New Trends in Nano-scale Metrology”. The school will be held in the Engineering Research Center for Extreme Ultraviolet Science and Technology (EUV-ERC), located in the Daryl B. Simons Building in the Foothills Campus from July 19 to July 23, 2010, 8:30 AM-12:30 PM.

The School will include lectures covering high resolution imaging, photo-lithography and spectrometry, with special emphasis in new developments utilizing extreme ultraviolet technology. The lectures will be followed by demonstrations in the EUV-ERC laboratories.

Seniors, graduate students and researchers are encouraged to apply. To register please send a message to: [marconi@engr.colostate.edu](mailto:marconi@engr.colostate.edu) before July 12. There is a limit of 20 participants so early registration is advised. This is an extra-curricular activity. There is no registration fee for participants from CSU.

Please feel free to disseminate this announcement among colleagues and students who may be interested.

